


<b>Search Notes</b>  	<b>Application/Control No.</b>  10586607	<b>Applicant(s)/Patent Under Reexamination</b>  KOHNO ET AL.
	<b>Examiner</b>  THOMAS DIAZ	<b>Art Unit</b>  3656

SEARCHED			
Class	Subclass	Date	Examiner
74	606R, 607	01/08/2009	/TD/
475	246, 230	01/08/2009	/TD/

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Search done in PALM/eDAN.	01/08/2009	/TD/
Search of US and Foreign patents done in EAST.	01/08/2009	/TD/
Consulted with Vinh Luong, primary in 74.	01/08/2009	/TD/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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